TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74LCX16373AFT

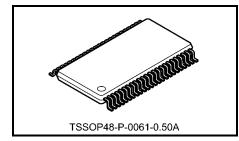
Low-Voltage 16-Bit D-Type Latch with 5-V Tolerant Inputs and Outputs

The TC74LCX16373AFT is a high-performance CMOS 16-bit D-type latch. Designed for use in 3.3-V systems, it achieves high-speed operation while maintaining the CMOS low power dissipation.

The device is designed for low-voltage (3.3 V) V_{CC} applications, but it could be used to interface to 5-V supply environment for both inputs and outputs.

This 16-bit D-type latch is controlled by a latch enable input (LE) and an output enable input (\overline{OE}) which are common to each byte. It can be used as two 8-bit latches or one 16-bit latch. When the \overline{OE} input is high, the outputs are in a high-impedance state.

All inputs are equipped with protection circuits against static discharge.

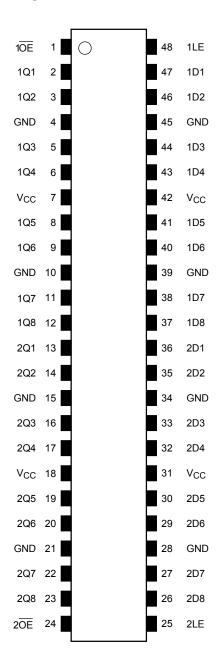


Weight: 0.25 g (typ.)

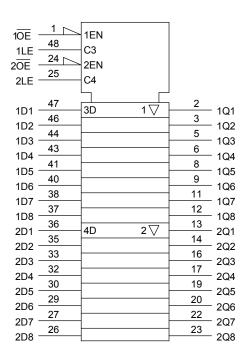
Features

- Low-voltage operation: V_{CC} = 2.0 to 3.6 V
- High-speed operation: $t_{pd} = 7.0 \text{ ns (max) (V}_{CC} = 3.0 \text{ to } 3.6 \text{ V)}$
- Ouput current: $|I_{OH}|/I_{OL} = 24 \text{ mA (min)} (V_{CC} = 3.0 \text{ V})$
- Latch-up performance: -500 mA
- Package: TSSOP
- Power-down protection provided on all inputs and outputs

Pin Assignment (top view)



IEC Logic Symbol



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Truth Table

	Outputs		
1OE	1LE	1D1-1D8	1Q1-1Q8
Н	Х	Х	Z
L	L	Х	Qn
L	Н	L	L
L	Н	Н	Н

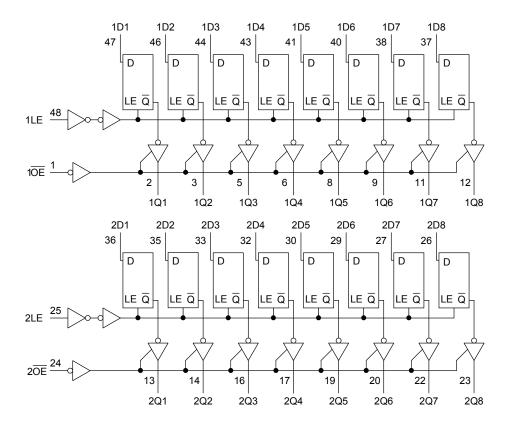
	Outputs		
2 OE	2LE	2D1-2D8	2Q1-2Q8
Н	Х	Х	Z
L	L	Х	Qn
L	Н	L	L
L	Н	Н	Н

X: Don't care

Z: High impedance

Qn: Q outputs are latched at the time when the LE input is taken to a low logic level

System Diagram





Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Power supply voltage	V _{CC}	−0.5 to 7.0	V
Input voltage	V _{IN}	-0.5 to 7.0	V
		-0.5 to 7.0 (Note 2)	
Output voltage	V _{OUT}	-0.5 to V_{CC} + 0.5	V
		(Note 3)	
Input diode current	I _{IK}	-50	mA
Output diode current	lok	±50 (Note 4)	mA
DC output current	I _{OUT}	±50	mA
Power dissipation	P_{D}	400	mW
DC V _{CC} /ground current per supply pin	I _{CC} /I _{GND}	±100	mA
Storage temperature	T _{stg}	-65 to 150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: Output in OFF state

Note 3: High or low state. IOUT absolute maximum rating must be observed.

Note 4: Vout < GND, Vout > Vcc

Operating Ranges (Note 1)

Characteristics	Symbol	Rating	Unit	
Power supply voltage	Vcc	2.0 to 3.6	V	
Fower supply voltage	VCC	1.5 to 3.6 (Note 2)	V	
Input voltage	VIN	0 to 5.5	V	
Output voltage	V _{OUT}	0 to 5.5 (Note 3)	V	
Output voltage		0 to V _{CC} (Note 4)	V	
Output current IOH/IO		±24 (Note 5)	mA	
Output current	I _{OH} /I _{OL}	±12 (Note 6)	IIIA	
Operating temperature	T _{opr}	-40 to 85	°C	
Input rise and fall time	dt/dv	0 to 10 (Note 7)	ns/V	

Note 1: The operating ranges must be maintained to ensure the normal operation of the device.

Unused inputs must be tied to either VCC or GND.

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Note 2: Data retention only

Note 3: Output in OFF state

Note 4: High or low state

Note 5: $V_{CC} = 3.0 \text{ to } 3.6 \text{ V}$

Note 6: $V_{CC} = 2.7 \text{ to } 3.0 \text{ V}$

Note 7: $V_{IN} = 0.8$ to 2.0 V, $V_{CC} = 3.0$ V



Electrical Characteristics

DC Characteristics ($Ta = -40 \text{ to } 85^{\circ}\text{C}$)

Characte	eristics	Symbol	Test (Test Condition V _{CC} (V)		Min	Max	Unit
la accidental de la constantina della constantin	H-level	V _{IH}		_	2.7 to 3.6	2.0	_	V
Input voltage	L-level	V _{IL}		_	2.7 to 3.6		0.8	V
				I _{OH} = -100 μA	2.7 to 3.6	V _{CC} 0.2		
	H-level	V _{OH}	$V_{IN} = V_{IH}$ or V_{IL}	I _{OH} = -12 mA	2.7	2.2	_	
				I _{OH} = -18 mA	3.0	2.4	_	
Output voltage				I _{OH} = -24 mA	3.0	2.2	_	V
		V _{OL}	V _{IN} = V _{IH} or V _{IL}	$I_{OL} = 100 \ \mu A$	2.7 to 3.6	_	0.2	
	L-level			I _{OL} = 12 mA	2.7	_	0.4	
	L-ievei			I _{OL} = 16 mA	3.0	_	0.4	
				I _{OL} = 24 mA	3.0	_	0.55	
Input leakage curre	ent	I _{IN}	V _{IN} = 0 to 5.5 V	V _{IN} = 0 to 5.5 V			±5.0	μΑ
3-state output OFF	state current	I _{OZ}	$V_{IN} = V_{IH}$ or V_{IL} $V_{OUT} = 0$ to 5.5 V		2.7 to 3.6	_	±5.0	μА
Power-off leakage	current	l _{OFF}	V _{IN} /V _{OUT} = 5.5 V		0	_	10.0	μΑ
Quiescent supply current			V _{IN} = V _{CC} or GND		2.7 to 3.6		20.0	
		Icc	$V_{IN}/V_{OUT} = 3.6 \text{ to } 5.5$	5 V	2.7 to 3.6	_	±20.0	μΑ
Increase in Icc per	input	Δlcc	$V_{IH} = V_{CC} - 0.6 V$		2.7 to 3.6		500	



AC Characteristics ($Ta = -40 \text{ to } 85^{\circ}\text{C}$)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Min	Max	Unit
Propagation delay time	t _{pLH}	Figure 1 Figure 2	2.7	_	8.0	20
(D-Q)	t _{pHL}	Figure 1, Figure 2	3.3 ± 0.3	1.5	7.0	ns
Propagation delay time	t _{pLH}	Figure 1 Figure 2	2.7	_	8.0	no
(LE-Q)	t _{pHL}	Figure 1, Figure 2	3.3 ± 0.3	1.5	7.0	ns
2 state output anable time	t _{pZL}	Figure 1, Figure 3	2.7	_	8.2	ns
3-state output enable time	t _{pZH}	Figure 1, Figure 3	3.3 ± 0.3	1.5	7.2	115
0 -4-444 dibl- 4i	t _{pLZ}	Figure 1 Figure 2	2.7	_	8.2	ne
3-state output disable time	t _{pHZ}	Figure 1, Figure 3	3.3 ± 0.3	1.5	7.2	ns
Minimum pulse width	+ (山)	(H) Figure 1, Figure 2	2.7	4.0	_	no
(LE)	t _w (H)		3.3 ± 0.3	3.0	_	ns
Minimum actus timo		Figure 1 Figure 2	2.7	2.5	_	ns
Minimum setup time	ις	ts Figure 1, Figure 2	3.3 ± 0.3	2.5	_	115
Ne : 1 He	4.	h Figure 1, Figure 2	2.7	1.5	_	20
Minimum hold time	ı u		3.3 ± 0.3	1.5	_	ns
Output to output skow	t _{osLH}	(Note)	2.7	_	_	ns
Output to output skew	t _{osHL}	(Note)	3.3 ± 0.3	_	1.0	115

Note: Parameter guaranteed by design.

 $(t_{OSLH} = |t_{PLHm} - t_{PLHn}|, t_{OSHL} = |t_{PHLm} - t_{PHLn}|)$

Dynamic Switching Characteristics

(Ta = 25°C, input: $t_r = t_f = 2.5 \text{ ns}, C_L = 50 \text{ pF}, R_L = 500 \Omega$)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Тур.	Unit
Quiet output maximum dynamic V _{OL}	V _{OLP}	$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$	3.3	0.8	V
Quiet output minimum dynamic V _{OL}	V _{OLV}	$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$	3.3	0.8	V

Capacitive Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Тур.	Unit
Input capacitance	C _{IN}	_	3.3	7	pF
Output capacitance	C _{OUT}	_	3.3	8	pF
Power dissipation capacitance	C _{PD}	f _{IN} = 10 MHz (Note)	3.3	25	pF

Note: CPD is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

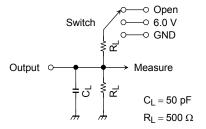
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Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/16 \text{ (per bit)}$



AC Test Circuit



Parameter	Switch
t _{pLH} , t _{pHL}	Open
t _{pLZ} , t _{pZL}	6.0 V
t _{pHZ} , t _{pZH}	GND
$t_{W}, t_{S}, t_{h},$	Open

Figure 1

AC Waveform

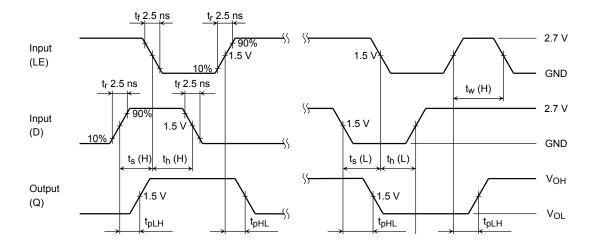


Figure 2 t_{pLH} , t_{pHL} , t_w , t_s , t_h

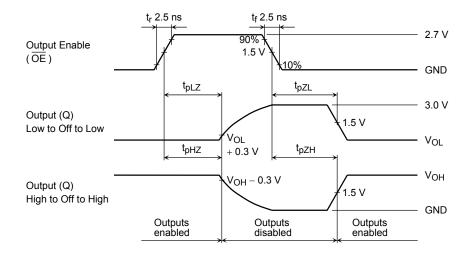


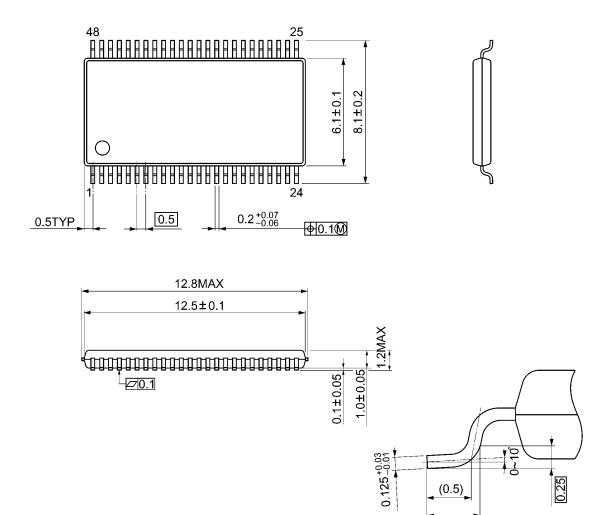
Figure 3 $t_{\text{pLZ}},\,t_{\text{pHZ}},\,t_{\text{pZL}},\,t_{\text{pZH}}$

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Package Dimensions

TSSOP48-P-0061-0.50A

Unit: mm



Weight: 0.25 g (typ.)

0.45~0.75

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20070701-EN GENERAL

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